

Taskforce on Solid Dielectrics

April 26, 2010 Meeting notes.

Acting Chairperson is Francois Soulard. Chris Ambrose could not be in attendance.

- Meeting called to order 4/26/10 at 10: 30 AM
- Presentation of IEEE Patent By-Laws clause 6 & inappropriate topics slides. Slides 1 to 4 of the presentation were presented.
- Introduction of people in attendance with company affiliation.
- Meeting minutes from the Denver meeting were reviewed. They can be found on the Switchgear web site under the RODE's report as Attachment #6.
- Review of action items from last meeting
 - Section 1: Definitions
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 - Section 2: Materials (Nenad Uzelac)
 - Nenad Uzelac reported that emails went out but he only received permission from Eaton to use the pictures of question in the document.
 - Question regarding use of pictures in the document. It could be considered as being commercial. Since this is just as a taskforce document is there a problem?
 - Editorial corrections were made within the group. These still have to be submitted to the chair.
 - Section 3: Applications and Environmental Issues (Medium Voltage only)
 - Their version has references to some standards in it. Does the group want this? References to other standards are appropriate.
 - Point made that the information that is in this section should go over to the testing section rather than the requirements session. The title "test" does not belong in this section.
 - Revision 3 of this group's paper was displayed. This paper should present what needs to be considered. Future groups would create the specific testing requirements based on the aspects this paper provides.
 - In each of these sections discussion should be held on what are standard conditions and what are severe requirements.
 - **ACTION ITEM:** Larry will expand on the application guide that they have created. Include suggested tests for the testing portion of the document will be at the bottom of this. Muench and DeCesaro will work on including those into the testing section.
 - Don Parker suggested having Frank Lambert and himself add some input to the thermal cycle section of this section and the testing section. **ACTION ITEM:** Muench requested that they send suggestions to himself or DeCesaro. They will try to merge and get back to Larry's group and Parker/Lambert for further discussion and editing prior to the fall 2010 meeting.
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 - Section 4: Testing and test matrix summary

- Testing matrix was an attempt to summarize the standard tests and what standards referenced them from other devices that use switchgear or solid dielectric switchgear standards. Then the application guide would discuss suggested passes. The copy of this should be in the minutes and be available.
 - **ACTION ITEM:** The next input from this group will be built off of the table that has already been created.
 - Should materials development tests be included such as inclined plane tests, etc? Yes, they should and will be discussed in some form.
 - Section 5: Standards
 - Presented last time. No update
 - Section 6: References
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- Royster-where is the direction of this going once put together. Is it going to subcommittee as a proposed standard or sent to other committee? Soulard replied that our purpose is to present to recommend a guide. Comment that it appears that we are making a guide though and would be the work of a project. This should be exploratory to bring technical discussion and dialect to bring to the sub-committee. Muench thought that this group was to create common clauses to be included into other areas using this as guideline to create a standard.
 - The form of the information will be brought to the sub-committee. Right now it is in an outline format.
- Other activities
 - No input
- Adjourned at 11:40 AM